

**IN THE CLAIMS**

Please add claims 26 through 28, as follows:

1           1. (Original) A thin film transistor, comprising a source electrode, a drain  
2 electrode, a gate electrode, and a semiconductor layer, wherein one of the source  
3 electrode, the drain electrode, and the gate electrode comprises an aluminum-based metal  
4 layer, a titanium layer, and a diffusion prevention layer interposed between the titanium  
5 and the aluminum-based layers.

1           2. (Original) The thin film transistor of claim 1, wherein the diffusion prevention  
2 layer and the titanium layer are orderly formed on opposite surfaces of the  
3 aluminum-based metal layer.

1           3. (Original) The thin film transistor of claim 1, wherein the diffusion prevention  
2 layer is a titanium nitride layer.

1           4. (Original) The thin film transistor of claim 3, wherein the titanium nitride layer  
2 contains 5 to 85 wt% of nitrogen.

1           5. (Original) The thin film transistor of claim 3, wherein the titanium nitride layer  
2 has a thickness of about 100 to 600Å.

1           6. (Original) The thin film transistor of claim 5, wherein the titanium nitride layer  
2           has a thickness of about 100 to 400Å.

1           7. (Original) The thin film transistor of claim 6, wherein the titanium nitride layer  
2           has a thickness of 200 to 400Å.

1           8. (Original) The thin film transistor of claim 7, wherein the titanium nitride layer  
2           has a thickness of about 300Å.

1           9. (Original) The thin film transistor of claim 1, wherein the aluminum-based  
2           metal layer is made of an aluminum alloy containing about 0.5 to 5 wt% of one element  
3           being selected from the group consisting of silicon, copper, neodymium, platinum, and  
4           nickel.

1           10. (Original) The thin film transistor of claim 9, wherein the aluminum-based  
2           metal layer is made of an aluminum-silicon alloy containing about 2 wt% of silicon.

1           11. (Original) A flat panel display, comprising a plurality of sub-pixels driven by  
2           thin film transistors, each of the thin film transistors comprising a source electrode, a  
3           drain electrode, a gate electrode, and a semiconductor layer, wherein at least one of the

4 source electrode, the drain electrode, and the gate electrode comprises an  
5 aluminum-based metal layer, a titanium layer, and a diffusion prevention layer interposed  
6 between the aluminum-based metal layer and the titanium layer.

1 12. (Original) The flat panel display of claim 11, wherein the diffusion  
2 prevention layer and the titanium layer are orderly formed on opposite sides of the  
3 aluminum-based metal layer.

1 13. (Original) The flat panel display of claim 11, wherein the diffusion  
2 prevention layer is a titanium nitride layer.

1 14. (Original) The flat panel display of claim 13, wherein the titanium nitride  
2 layer contains 5 to 85 wt% of nitrogen.

1 15. (Original) The flat panel display of claim 13, wherein the titanium nitride  
2 layer has a thickness of about 100 to 600Å.

1 16. (Original) The flat panel display of claim 15, wherein the titanium nitride  
2 layer has a thickness of about 100 to 400Å.

1 17. (Original) The flat panel display of claim 16, wherein the titanium nitride

2 layer has a thickness of 200 to 400Å.

1 18. (Original) The flat panel display of claim 17, wherein the titanium nitride  
2 layer has a thickness of about 300Å.

1 19. (Original) The flat panel display of claim 11, wherein the aluminum-based  
2 metal layer is made of an aluminum alloy containing about 0.5 to 5 wt% of one element  
3 being selected from the group consisting of silicon, copper, neodymium, platinum, and  
4 nickel.

1 20. (Original) The flat panel display of claim 19, wherein the aluminum-based  
2 metal layer is made of an aluminum-silicon alloy containing about 2 wt% of silicon.

1 21. (Original) A flat panel display, comprising:  
2 driving circuits disposed along edges of said display;  
3 a plurality of sub-pixels driven by thin film transistors; and  
4 conductive lines connecting the driving circuits disposed along edges of said  
5 display to each of said plurality of sub-pixels, wherein said conductive lines comprise an  
6 aluminum-based metal layer, a titanium layer, and a diffusion prevention layer interposed  
7 between the aluminum-based metal layer and the titanium layer.

1           22. (Original) The flat panel display of claim 21, wherein the diffusion  
2 prevention layer and the titanium layer are orderly formed on opposite sides of the  
3 aluminum-based metal layer.

1           23. (Original) The flat panel display of claim 21, wherein the diffusion  
2 prevention layer is a titanium nitride layer.

1           24. (Original) The display of claim 23, said titanium nitride layer is 300 Å thick.

1           25. (Original) The display of claim 24, said conductive lines being subjected to a  
2 heat treatment of 380°C.

1           26. (New) A process for making a flat panel display, comprising:  
2 disposing driving circuits along edges of said display;  
3 arranging a plurality of sub-pixels driven by thin film transistors; and  
4 operatively connecting electrically conductive lines between the driving circuits  
5 disposed along edges of said display and each of said plurality of sub-pixels, wherein said  
6 conductive lines comprise an aluminum-based metal layer, a titanium layer, and a  
7 diffusion prevention layer interposed between the aluminum-based metal layer and the  
8 titanium layer.

1           27. (New) The process of claim 26, comprised of orderly forming the diffusion  
2 prevention layer and the titanium layer on opposite sides of the aluminum-based metal  
layer.

1           28. (New) The process of claim 26, wherein the diffusion prevention layer is a  
2 titanium nitride layer.